Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 1. (Currently Amended) A semiconductor device structure, comprising:
 - a substrate defining a substantially horizontal plane;
 - a common source region;
 - a common drain region;
- a gate electrode disposed on said substrate and being electrically insulated therefrom, said gate electrode positioned vertically between said <u>common</u> source region and said <u>common</u> drain region; and
- a plurality of semiconducting nanotubes each including a first end <u>physically and</u> electrically coupled with said <u>common</u> source region, a second end <u>physically and</u> electrically coupled with said <u>common</u> drain region, and a channel region extending vertically through said gate electrode between said <u>common</u> source region and said <u>common</u> drain region, said channel region being electrically insulated from said gate electrode, and said gate electrode configured to receive a control voltage effective to regulate current flow through said channel region of a respective one of said semiconducting nanotubes between said <u>common</u> source region and said <u>common</u> drain region.
- 2. (Currently Amended) The semiconductor device structure of claim 1 wherein said <u>common</u> source is composed of a catalyst material effective for growing said semiconducting nanotubes.
- 3. (Currently Amended) The semiconductor device structure of claim 1 wherein said <u>common</u> drain is composed of a catalyst material effective for growing said semiconducting nanotubes.

- 4. (Currently Amended) The semiconductor device structure of claim 1 further comprising: an insulating layer disposed between said <u>common</u> drain and said gate electrode for electrically isolating said drain from said gate electrode.
- 5. (Currently Amended) The semiconductor device structure of claim 1 further comprising: an insulating layer disposed between said <u>common</u> source and said gate electrode for electrically isolating said source from said gate electrode.
- 6. (Previously Presented) The semiconductor device structure of claim 1 wherein said at least one semiconducting nanotube is composed of arranged carbon atoms.
- 7. (Cancelled)
- 8. (Previously Presented) The semiconductor device structure of claim 1 wherein said at least one semiconducting nanotube is oriented substantially perpendicular to said horizontal plane.
- 9. (Cancelled)
- 10. (Previously Presented) The semiconductor device structure of claim 1 wherein said gate dielectric is disposed on said semiconducting nanotubes.
- 11-24. (Cancelled)
- 25. (Previously Presented) A semiconductor device structure, comprising:
 - a substrate;
 - an electrically-conductive first plate on said substrate;
 - an electrically-conductive second plate disposed vertically above said first plate;
 - an electrically-conductive layer disposed between said first and second plates;

at least one nanotube having an end electrically coupled with said first plate for increasing an effective area of said first plate, said at least one nanotube positioned in said electrically-conductive layer; and

a dielectric layer coating said length of said at least one nanotube such that said at least one nanotube is electrically isolated from said electrically-conductive layer and said second plate.

26. (Original) The semiconductor device structure of claim 25 wherein said at least one nanotube has a conducting molecular structure.

27. (Original) The semiconductor device structure of claim 25 wherein said at least one nanotube has a semiconducting molecular structure.

28. (Previously Presented) The semiconductor device structure of claim 25 wherein said dielectric layer encases said at least one nanotube.

29-33. (Cancelled)